

Multilayer Chip Ceramic Inductor



◆ **Features**

- 1、 Monolithic Structure for high reliability
- 2、 High self-resonant frequency
- 3、 Excellent solderability and high heat resistance
- 4、 RoHS Compliant.



◆ **Application**

- 1、 RF Circuit of in telecommunication and other Equipments

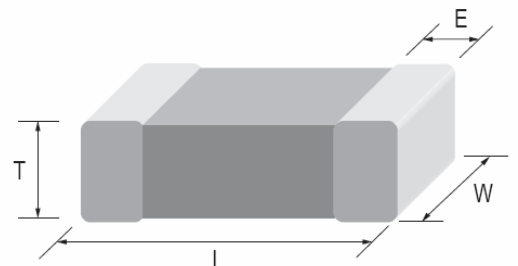
◆ **PRODUCT IDENTIFICATION**

CMCC 0603 C 1N0 S S P
(1) (2) (3) (4) (5) (6) (7)

- (1) Series Type
- (2) Chip Size (mm) :Length X Width
- (3) Material Code
- (4) Inductance: 1N0=1nH; 10N=10nH
R10=100nH
- (5) Inductance Tolerance: B=±0.1; C=±0.2; S=±0.3;
G=±2%; H=±3%; J=±5%
- (6) Company Code
- (7) Packaging:P–Embossed paper tape, 7" reel
E- Embossed plastic tape, 7" reel

◆ **Dimensions Unit: mm**

Size(EIA)	L	W	T	E
	0.60±0.05	0.30±0.05	0.30±0.05	0.20±0.10



◆ Specifications

Part Number	Inductance (nH)	Min. Quality Factor (Q)	L, Q Test Freq. L/Q(MHz)	Typical Q @ Freq. (GHz)					Min. Self-resonant Frequency (MHz)	Max. DC Resistance (Ω)	Max. Rated Current (mA)
				0.5	0.8	1.8	2.0	2.4			
				Q							
CMCC0603 Series											
CMCC0603C0N6◇SP	0.6	13	500	>24	>32	>54	>57	>65	10000	0.06	600
CMCC0603C0N7◇SP	0.7	13	500	>24	>32	>54	>57	>65	10000	0.06	550
CMCC0603C0N8◇SP	0.8	13	500	>24	>32	>54	>57	>65	10000	0.07	550
CMCC0603C0N9◇SP	0.9	13	500	>24	>32	>54	>57	>65	10000	0.07	550
CMCC0603C1N0◇SP	1.0	13	500	24	32	54	57	65	10000	0.08	520
CMCC0603C1N1◇SP	1.1	13	500	19	26	45	47	55	10000	0.11	440
CMCC0603C1N2◇SP	1.2	13	500	19	25	43	44	52	10000	0.12	420
CMCC0603C1N3◇SP	1.3	13	500	19	25	40	42	47	10000	0.12	420
CMCC0603C1N4◇SP	1.4	13	500	19	24	39	41	47	10000	0.11	440
CMCC0603C1N5◇SP	1.5	13	500	19	24	39	41	46	10000	0.12	420
CMCC0603C1N6◇SP	1.6	13	500	19	24	39	41	46	10000	0.13	410
CMCC0603C1N7◇SP	1.7	13	500	19	24	39	41	46	10000	0.15	380
CMCC0603C1N8◇SP	1.8	13	500	19	24	39	41	46	10000	0.15	380
CMCC0603C1N9◇SP	1.9	13	500	18	24	38	40	45	10000	0.18	350
CMCC0603C2N0◇SP	2.0	13	500	17	24	38	39	44	10000	0.23	300
CMCC0603C2N1◇SP	2.1	13	500	17	24	37	39	44	10000	0.24	300
CMCC0603C2N2◇SP	2.2	13	500	17	24	38	40	43	10000	0.25	290
CMCC0603C2N3◇SP	2.3	13	500	17	24	37	39	43	10000	0.20	330
CMCC0603C2N4◇SP	2.4	13	500	17	23	36	38	42	10000	0.22	310
CMCC0603C2N5◇SP	2.5	13	500	17	23	35	36	40	9600	0.20	330
CMCC0603C2N6◇SP	2.6	13	500	17	22	34	35	39	9400	0.20	330
CMCC0603C2N7◇SP	2.7	13	500	17	22	34	35	39	9200	0.22	310
CMCC0603C2N8◇SP	2.8	13	500	17	22	34	35	39	8900	0.24	300
CMCC0603C2N9◇SP	2.9	13	500	17	22	34	35	39	8800	0.26	280

◆ Specifications

Part Number	Inductance (nH)	Min. Quality Factor (Q)	L, Q Test Freq. L/Q(MHz)	Typical Q @ Freq. (GHz)					Min. Self-resonant Frequency (MHz)	Max. DC Resistance (Ω)	Max. Rated Current (mA)
				0.5	0.8	1.8	2.0	2.4			
				Q							
CMCC0603 Series											
CMCC0603C2N9◇SP	2.9	13	500	17	22	34	35	39	8800	0.26	280
CMCC0603C3N0◇SP	3.0	13	500	17	22	34	35	39	8600	0.26	280
CMCC0603C3N1◇SP	3.1	13	500	17	22	34	35	39	8500	0.28	270
CMCC0603C3N2◇SP	3.2	13	500	17	22	33	35	39	8200	0.28	270
CMCC0603C3N3◇SP	3.3	13	500	18	23	34	36	40	8100	0.30	270
CMCC0603C3N4◇SP	3.4	13	500	17	23	33	35	39	8000	0.30	270
CMCC0603C3N5◇SP	3.5	13	500	17	23	33	35	39	7900	0.34	250
CMCC0603C3N6◇SP	3.6	13	500	16	23	33	35	39	7700	0.38	240
CMCC0603C3N7◇SP	3.7	13	500	16	23	33	35	38	7600	0.40	230
CMCC0603C3N8◇SP	3.8	13	500	16	22	33	35	38	7500	0.42	230
CMCC0603C3N9◇SP	3.9	13	500	16	22	33	35	38	7400	0.42	230
CMCC0603C4N3◇SP	4.3	13	500	16	21	32	34	37	6800	0.44	220
CMCC0603C4N7◇SP	4.7	13	500	16	22	33	35	38	6200	0.45	220
CMCC0603C5N1◇SP	5.1	13	500	17	22	34	36	38	5900	0.46	210
CMCC0603C5N6◇SP	5.6	13	500	16	21	33	34	37	5500	0.46	210
CMCC0603C6N2◇SP	6.2	13	500	18	23	34	35	37	5100	0.48	210
CMCC0603C6N8◇SP	6.8	13	500	17	22	32	33	35	4900	0.50	200
CMCC0603C7N5◇SP	7.5	13	500	16	21	31	33	34	4700	0.50	200
CMCC0603C8N2◇SP	8.2	13	500	16	21	31	32	34	4300	0.56	190
CMCC0603C9N1◇SP	9.1	13	500	16	20	30	31	32	4100	0.72	170
CMCC0603C10N◇SP	10	13	500	16	20	28	29	31	3800	0.80	160
CMCC0603C12N◇SP	12	13	500	16	20	27	28	28	3400	0.80	160
CMCC0603C15N◇SP	15	13	500	15	19	24	24	23	2600	0.85	160
CMCC0603C18N◇SP	18	13	500	15	19	23	24	22	2300	1.00	140

◆ Specifications

Part Number	Inductance (nH)	Min. Quality Factor (Q)	L, Q Test Freq. L/Q(MHz)	Typical Q @ Freq. (GHz)					Min. Self-resonant Frequency (MHz)	Max. DC Resistance (Ω)	Max. Rated Current (mA)
				0.5	0.8	1.8	2.0	2.4			
				Q							
CMCC0603 Series											
CMCC0603C22N◇SP	22	13	500	15	19	22	23	20	1900	1.20	130
CMCC0603C27N◇SP	27	13	500	15	19	15	13	8	1800	1.60	120
CMCC0603C33N◇SP	33	11	300	14	15	8	5	-	1800	2.20	110
CMCC0603C39N◇SP	39	11	300	14	15	6	-	-	1600	2.30	100
CMCC0603C47N◇SP	47	11	300	14	15	-	-	-	1500	2.60	100
CMCC0603C56N◇SP	56	11	300	13	13	-	-	-	1400	2.80	80
CMCC0603C68N◇SP	68	11	300	13	11	-	-	-	1200	3.20	80
CMCC0603C82N◇SP	82	10	300	12	10	-	-	-	1100	3.80	70
CMCC0603CR10◇SP	100	10	300	12	10	-	-	-	1000	4.00	60
CMCC0603CR12◇SP	120	9	300	12	8	-	-	-	1000	5.00	50

Note: ◇: Please specify the inductance tolerance. For L≤6.2nH, choose B=±0.1nH, C=±0.2nH or S=±0.3nH; For L>6.2nH, choose G=±2%, H=±3% or J=5%.

◆ General Technical Data

Operating Temperature Range	-55°C ~ +125°C
Storage Condition	Less than 40°C and 70% RH
Soldering Method	Reflow or Wave Soldering

◆ **Composition / Information on Ingredients**

Product Structure: See Fig.1, Fig. 2 and Fig. 3



Fig.1 Shape

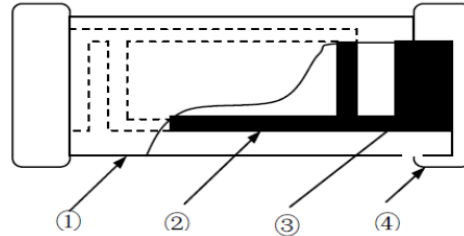


Fig.2 Body Structure

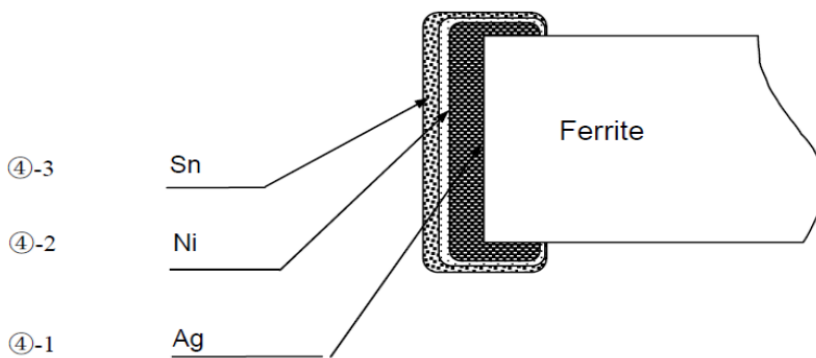


Fig. 3 Structure of Electro-plating

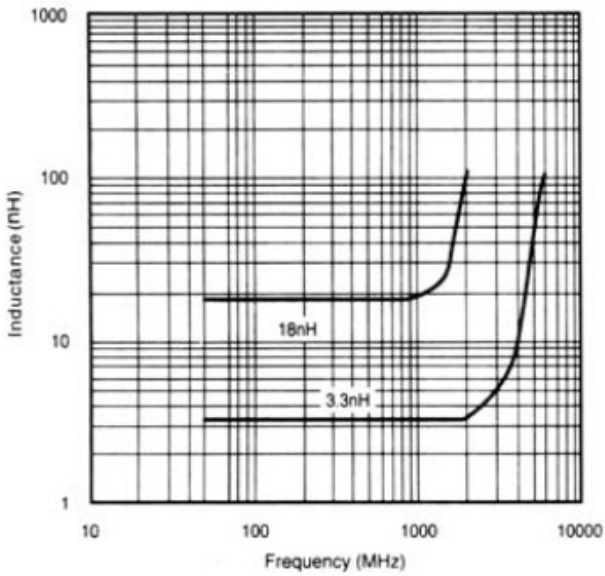
Composition/Information on the Components		
Code	Material	Main Components
①	Ceramic	Boron Silicate, Al ₂ O ₃ , Secret
②	Inner Coil	Silver (Ag)
③	Pull-out Electrode	Silver (Ag)
④-1	Terminal Electrode	Silver (Ag)
④-2	Electrode-plating: Nickel plating	Nickel (Ni)
④-3	Electrode-plating: Sn plating	Tin (Sn)

Compositions Wt Rate (Wt%) of Material		
Material	Wt Rate (Wt%)	CAS No.
Boron Silicate	51~65	65997-18-4
Al ₂ O ₃	14~17	1344-28-1
Secret	0~5	-
Ag	9~29	7440-22-4
Nickel	1.8~2.3	7440-02-0
Tin	3.6~4.7	7440-31-5

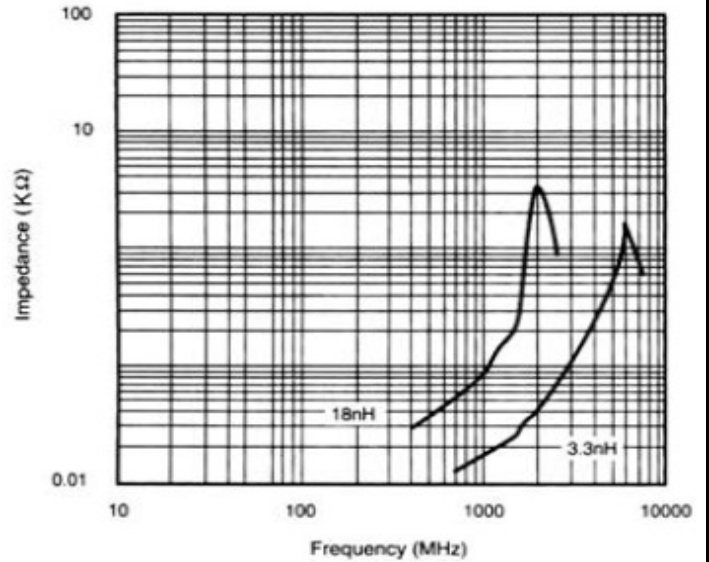
◆ TYPICAL ELECTRICAL CHARACTERISTICS

CMCC0603 Series

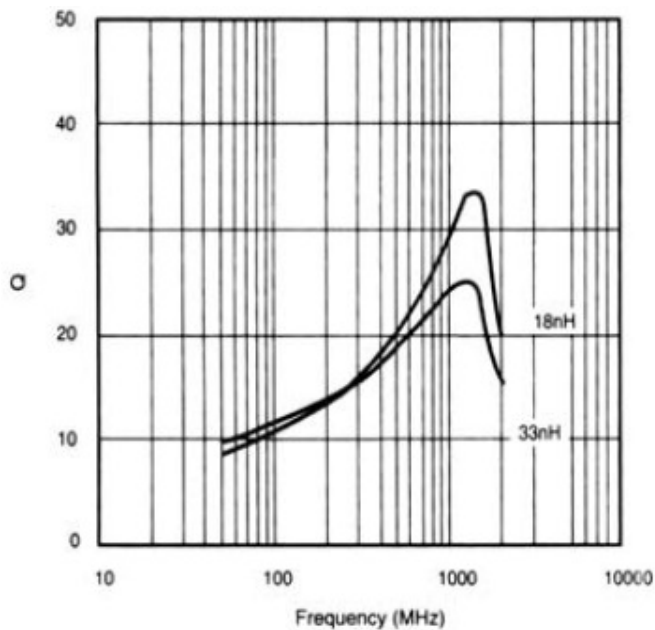
Inductance vs. Frequency Characteristics



Impedance vs. Frequency Characteristics



Q vs. Frequency Characteristics



◆ **Test and Measurement Procedures**

1、 Test Conditions

- A、 unless otherwise specified, the standard atmospheric conditions for measurement/test as:
 - a.Ambient Temperature: $20\pm 15^{\circ}\text{C}$
 - b.Relative Humidity: $65\pm 20\%$
 - c.Air Pressure: 86kPa to 106kPa
- B、 If any doubt on the results, measurements/tests should be made within the following limits:
 - a.Ambient Temperature: $20\pm 2^{\circ}\text{C}$
 - b.Relative Humidity: $65\pm 5\%$
 - c.Air Pressure: 86kPa to 106kPa

2、 Visual Examination

- a .Inspection Equipment: 20× magnifier

3、 Electrical Test

A、 DC Resistance (DCR)

- a.Refer to Appendix A.
- b.Test equipment (Analyzer): High Accuracy Milliohmmeter-HP4338B or equivalent.

B、 Inductance (L)

- a.Refer to Appendix A.
- b.Test equipment: High Accuracy RF Impedance /Material Analyzer-E4991A+HP16192A or equivalent.
- c.Test signal: -20dBm or 50mV
- d.Test frequency refers to Appendix A.

C、 Q Factor (Q)

- a.Refer to Appendix A.
Test equipment: High Accuracy RF Impedance /Material Analyzer-E4991A+HP16192A or equivalent.
- b.Test signal: -20dBm or 50mV
- c.Test frequency refers to Appendix A.

4、 Self-Resonant Frequency (SRF)

- A、 Refer to Appendix A.
Test equipment: High Accuracy RF Impedance /Material Analyzer- E4991A+HP16192A or Agilent E5071C Network analyzer(when SRF > 3GHz).
- B、 Test signal: -20dBm or 50 mV

5、 Rated Current

- A、 Refer to Appendix A.
- B、 Test equipment (see Fig1): Electric Power, Electric current meter, Thermometer.
- C、 Measurement method (see Fig1):
 - a.Set test current to be 0mA.
 - b.Measure initial temperature of chip surface.
 - c.Gradually increase voltage and measure chip temperature for corresponding current.
- D、 Definition of Rated Current(Ir): Ir is direct electric current as chip surface temperature rose just 20°C against chip initial surface temperature(T_a) (see Fig2).

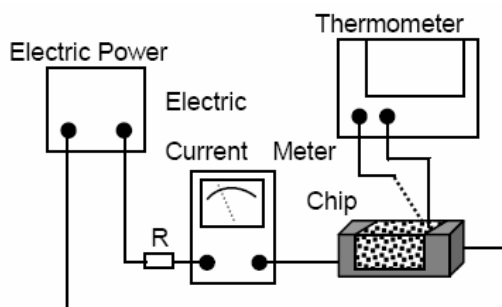


Fig1

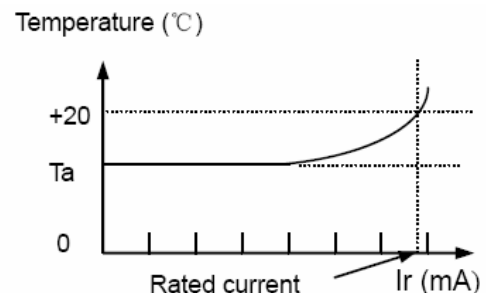
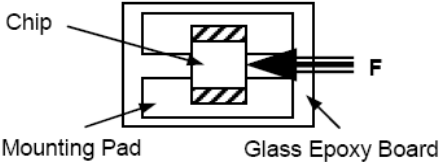
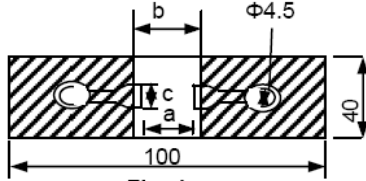
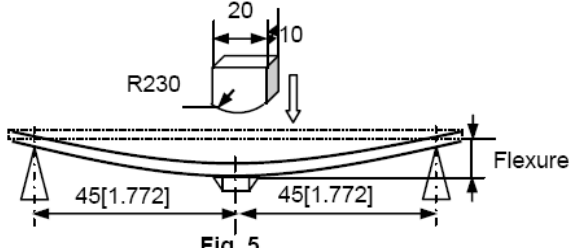
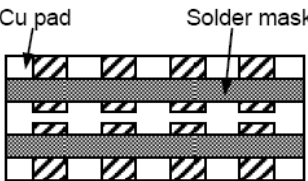
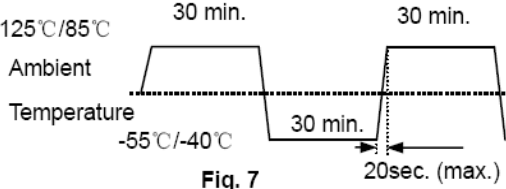


Fig2

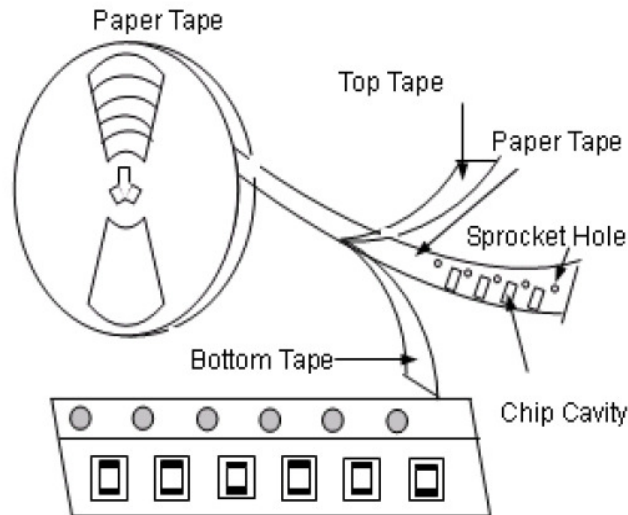
◆ Reliability Test

Items	Requirements	Test Methods and Remarks								
1. Terminal Strength	<p>No removal or split of the termination or other defects shall occur.</p>  <p>Chip Mounting Pad Glass Epoxy Board Fig.3</p>	<ol style="list-style-type: none"> Solder the inductor to the testing jig (glass epoxy board shown in Fig. 3) using leadfree solder. Then apply a force in the direction of the arrow. 5N force for 0603 series. Keep time: 10±1s Speed: 1.0mm/s. 								
2. Resistance to Flexure	<p>No visible mechanical damage.</p> <table border="1" data-bbox="284 723 743 815"> <thead> <tr> <th>Type</th> <th>a</th> <th>b</th> <th>c</th> </tr> </thead> <tbody> <tr> <td>0603[0201]</td> <td>1.0</td> <td>3.0</td> <td>1.2</td> </tr> </tbody> </table> <p>Unit: mm [inch]</p>  <p>Fig. 4</p>	Type	a	b	c	0603[0201]	1.0	3.0	1.2	<ol style="list-style-type: none"> Solder the inductor to the test jig (glass epoxy board shown in Fig. 4) Using a leadfree solder. Then apply a force in the direction shown Fig.5 Flexure: 2mm. Pressurizing Speed: 0.5mm/sec. Keep time: 30 sec.  <p>Fig. 5</p>
Type	a	b	c							
0603[0201]	1.0	3.0	1.2							
3. Vibration	<ol style="list-style-type: none"> No visible mechanical damage. Inductance change: Within ±10%. Q factor change: Within ±20%.  <p>Cu pad Solder mask Glass Epoxy Board Fig. 6</p>	<ol style="list-style-type: none"> Solder the inductor to the testing jig (glass epoxy board shown in Fig.6) using leadfree solder. The inductor shall be subjected to a simple harmonic motion having total amplitude of 1.5mm, the frequency being varied uniformly between the approximate limits of 10 and 55 Hz. The frequency range from 10 to 55 Hz and return to 10 Hz shall be traversed in approximately 1 minute. This motion shall be applied for a period of 2 hours in each 3 mutually perpendicular directions (total of 6 hours). 								
4. Dropping	<ol style="list-style-type: none"> No visible mechanical damage. Inductance change: Within ±10%. Q factor change: Within ±20%. 	Drop chip inductor 10 times on a concrete floor from a height of 100 cm.								
5. Temperature	Inductance change should be within ±10% of initial value measuring at 20°C.	Temperature range: -55°C to +125°C, Reference temperature: 20°C								
6. Solderability	<ol style="list-style-type: none"> No visible mechanical damage. Wetting shall exceed 75% coverage for 0603 series; exceed 95% for others 	<ol style="list-style-type: none"> Solder temperature: 240±2°C Duration: 3 sec. Solder: Sn/3.0Ag/0.5Cu. Flux: 25% Resin and 75% ethanol in weight. 								
7. Resistance to Soldering Heat	<ol style="list-style-type: none"> No visible mechanical damage. Wetting shall exceed 75% coverage for 0603 series; exceed 95% coverage for others Inductance change: Within ±10%. Q factor change: Within ±20%. 	<ol style="list-style-type: none"> Solder temperature: 260±3°C Duration: 5 sec. Solder: Sn/3.0Ag/0.5Cu. Flux: 25% Resin and 75% ethanol in weight. The chip shall be stabilized at normal condition for 1~2 hours before measuring. 								

<p>8. Thermal Shock</p>	<p>① No mechanical damage. ② Inductance change: Within $\pm 10\%$. ③ Q factor change: Within $\pm 20\%$.</p>  <p>Fig. 7</p>	<p>① Temperature, Time: (See Fi.7) -55°C for 30±3 min→125°C for 30±3min, ② Transforming interval: Max. 20 sec. ③ Tested cycle: 100 cycles. ④ The chip shall be stabilized at normal condition for 1~2 hours before measuring.</p>
<p>9. Resistance to Low Temperature</p>	<p>① No mechanical damage. ② Inductance change: Within $\pm 10\%$. ③ Q factor change: Within $\pm 20\%$.</p>	<p>① Temperature: -55±2°C, ② Duration: 1000⁺²⁴ hours. ③ The chip shall be stabilized at normal condition for 1~2 hours before measuring.</p>
<p>10. Resistance to High Temperature</p>	<p>① No mechanical damage. ② Inductance change: Within $\pm 10\%$. ③ Q factor change: Within $\pm 20\%$.</p>	<p>① Temperature: 125±2°C, ② Duration: 1000⁺²⁴ hours. ③ The chip shall be stabilized at normal condition for 1~2 hours before measuring.</p>
<p>11. Damp Heat (Steady States)</p>	<p>① No visible mechanical damage. ② Inductance change: Within $\pm 10\%$. ③ Q factor change: Within $\pm 20\%$.</p>	<p>① Temperature: 60±2°C ② Humidity: 90% to 95% RH. ③ Duration: 1000⁺²⁴ hours. ④ The chip shall be stabilized at normal condition for 1~2 hours before measuring.</p>
<p>12. Loading Under Damp Heat</p>	<p>① No visible mechanical damage. ② Inductance change: Within $\pm 10\%$. ③ Q factor change: Within $\pm 20\%$.</p>	<p>① Temperature: 60±2°C ② Humidity: 90% to 95% RH. ③ Duration: 1000⁺²⁴ hours. ④ Applied current: Rated current. ⑤ The chip shall be stabilized at normal condition for 1~2 hours before measuring.</p>
<p>13. Loading at High Temperature (Life Test)</p>	<p>① No visible mechanical damage. ② Inductance change: Within $\pm 10\%$. ③ Q factor change: Within $\pm 20\%$.</p>	<p>① Temperature: 125±2°C, ② Duration: 1000⁺²⁴ hours. ③ Applied current: Rated current. ④ The chip shall be stabilized at normal condition for 1~2 hours before measuring.</p>

◆ Packaging

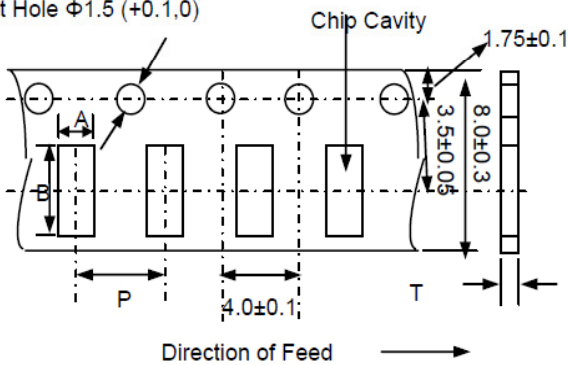
(1) Taping Drawings (Unit: mm)



Remark: The sprocket holes are to the right as the tape is pulled toward the user.

(2) Taping Dimensions (Unit: mm)

Sprocket Hole $\Phi 1.5 (+0.1, 0)$



Paper Tape

Type	A	B	P	T max	Quantity
0603(0201)	0.4±0.1	0.7±0.1	2.0±0.05	0.55	15K

(3) Reel Dimensions (Unit: mm)

